Industrial Electronics

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The p-n Junction

- A p-n junction is formed when p-type semiconductor is brought in metallurgical or physical contact with n-type semiconductor.
- p-region has more holes concentration.
- n- region has more electrons concentration.

The p-n Junction

- In p-region holes are majority carriers and electrons are minority carriers.
- In n-region electrons are majority carriers and holes are minority carriers.

Depletion Layer





Thyristor

- The term Thyristor denotes a family of semiconductor devices used for power control in DC and AC system.
- Thyristor is a family of semiconductor devices like SCR, TRIAC, Diac, Slicon controlled Switch (SCS), Programmable Unijunction Transistor (PUT) etc.
- The use of SCR is so vast that over the years, the word thysristor has become synonymous with SCR.

Thyristor

- Thyristor has characteristics similar to a thyratron tube.
- The name Thyristor is derived from combination of THYRatron and transISTOR.
- Thyristor:
 - Constitutes three or more p-n junctions.
 - Has two stable states, an ON state and an OFF state.
 - Can change its state from one to another.

SCR (Silicon Controlled Rectifier)







Thyrister (SCR)

- It is four layer, three junction, p-n-p-n semiconductor switching device.
- It has three terminals; Anode, Cathode and Gate.
- Gate terminal is usually kept near cathode terminal.
- SCRs of voltage rating 10 kV and rms current rating of 3000A with corresponding power handling capacity of 30MW are available.

Thyrister (SCR)

- SCR is so called because silicon is used for its construction and used as controlled rectifier.
- Unlike diode, a thyristor also blocks the current flow from anode to cathode until it is triggered by gate signal.



- Forward Blocking Mode
 - Anode is made +ve w.r.t. Cathode , Gate open.
 - \circ J₁, J₃ are forward biased, J₂ is reverse biased.
 - Forward leakage current flows.
 - SCR offers high impedance.
 - It can be treated as an open switch.

- Forward Conduction Mode
 - When anode to cathode forward voltage is increased, Junction J₂ will have an avalanche breakdown at Forward Break over Voltage V_{BO.}
 - Voltage drop across the thyristor is of the order of 1 to 2 V, depending on SCR rating.
 - Anode current is limited by load impedance.
 - Thyristor acts as a closed switch.

- Reverse Blocking Mode
 - Cathode is made +ve w.r.t. Anode, Gate open.
 - \circ J₁, J₃ are reverse biased, J₂ is forward biased.
 - Device behaves as two diodes connected in series with reverse voltage applied.
 - Reverse leakage current of few milli amperes flow.
 - At reverse breakdown voltage V_{BR}, an avalanche occurs at J₁ and J_{3.}
 - Reverse current increases rapidly.
 - Large current with V_{BR} gives rise to more losses.
 - This may lead to damage of SCR.

- Gate Triggering
 - Simple, reliable and efficient method to turn on the SCR and is mostly used.
 - Positive gate voltage between gate and cathode is applied.
 - Charges are injected in to inner p layer
 - The voltage at which forward break over occurs, is reduced.
 - Higher the gate current, lower is the forward break over voltage.
 - Typical gate current is 20 to 200 mA.

• Gate Triggering Continued...

- With positive gate current, p layer is flooded with electrons from cathode as n layer is heavily doped as compared to gate p layer.
- Some of these electrons reach junction J_{2.}
- Due to this, width of depletion layer near junction J₂ is reduced and it breaks down at lower voltage.
- Reverse biased junction J_2 no longer exists.
- If gate current is removed, anode to cathode current remains unaffected.



• Latching Current:

 Minimum value of anode current which SCR must attain during turn on process, to maintain conduction when gate signal is removed.

Holding Current:

- Minimum value of anode current below which it must fall for turning off the thyristor.
- Latching current is associated with turn on process and Holding current with turn off process



CIICUM - 1

where

and

In the off-state of a transistor, collector current I_C is related to emitter current I_E as

$$I_C = \alpha I_E + I_{CBO}$$

where α is the common-base current gain and I_{CBO} is the common-base leakage current of collector-base junction of a transistor.

For transistor Q_1 in Fig. current I_{C1} . Therefore, for Q_1 , (i)

$$\begin{split} I_{C1} &= \alpha_1 I_a + I_{CBO1} \\ \alpha_1 &= \text{common-base current gain of } Q_1 \\ I_{CBO1} &= \text{common-base leakage current of } Q_1. \end{split}$$

Similarly, for transistor Q_2 , the collector current I_{C2} is given by

where

 $I_{C2} = \alpha_2 I_k + I_{CBO2}$ $\alpha_2 = \text{common-base current gain of } Q_2$ $I_{CBO2} = \text{common-base leakage current of } Q_2$ $I_k = \text{emitter current of } Q_2.$

and

The sum of two collector currents given by Eqs. (i) and (ii) is equal to the external circuit current I_a entering at anode terminal A.

or

:.
$$I_a = I_{C1} + I_{C2}$$

 $I_a = \alpha_1 I_a + I_{CBO1} + \alpha_2 I_k + I_{CBO2}$
(iii)

··· (ii)

When gate current is applied, then $I_k = I_a + I_g$. Substituting this value of I_k in Eq. (iii) gives

$$\begin{split} I_{a} &= \alpha_{1} I_{a} + I_{CBO1} + \alpha_{2} (I_{a} + I_{g}) + I_{CBO2} \\ I_{a} &= \frac{\alpha_{2} I_{g} + I_{CBO1} + I_{CBO2}}{1 - (\alpha_{1} + \alpha_{2})} \end{split}$$

or

- For a silicon transistor, current gain α is very low at low emitter current.
- With an increase in emitter current, α builds up rapidly.
- With $I_g=0$, $(\alpha_1 + \alpha_2)$ is very low.
- If emitter current is increased so that ($\alpha_1 + \alpha_2$) approaches unity, I_a would tend to become infinity.



DIAC

- When voltage across the terminals exceeds the breakover voltage, the four out of five layers conduct.
- Name is derived from Dlode that can work on AC.
- It's terminals are interchangeable.
- Turn on voltage is around 30 V.
- While conducting, voltage drop across it is around 3 V





Modes of Operation

T₂ Positive and Gate Positive



T₂ Positive and Gate Positive

- Junction p₁ n₁ and p₂ n₂ are forward biased.
- Junction $n_1 p_2$ is reverse biased.
- Gate current injects sufficient carriers in p₂ layer and Junction n₁ - p₂ breaks down.
- Device is more sensitive in this mode.

T₂ Positive and Gate Negative



T₂ Positive and Gate Negative

- Junction $p_1 n_1$ and $p_2 n_2$ are forward biased.
- Junction $n_1 p_2$ is reverse biased.
- Gate current flows through $p_2 n_3$ junction.
- Initially TRIAC current flows through p₁ n₁ p₂ n_{3.}
- Due to conduction of p₁ n₁ p₂ n₃, the potential of left side of the layer p₂ rises towards anode potential of T₂.

T₂ Positive and Gate Negative

- Potential gradient exists between across the layer p_{2.}
- Left side being at higher potential, the current is established in p₂ layer from left to right.
- > $p_1 n_1 p_2 n_2$ start conducting like normal SCR.
- > $p_1 n_1 p_2 n_3$ may be regarded as pilot SCR.
- Device is less sensitive in this mode, so require more gate current.

T₂ Negative and Gate Positive



T₂ Negative and Gate Positive

- Gate current forward biases the p₂ n₂ junction.
- Layer n_2 injects electrons in p_2 layer.
- Reverse biased junction $n_1 p_1$ breaks down.
- $P_2 n_1 p_1 n_4$ is completely turned on.
- As the TRIAC is turned on by remote gate n₂ the device is less sensitive.

T2 and Gate is Negative


T2 and Gate is Negative

- n₃ acts as remote gate.
- Gate current flows from p₂ to n₃ as in normal Thyristor.
- Reverse biased junction $n_1 p_1$ breaks down.
- Structure $p_2 n_1 p_1 n_4$ is turned on.
- Device is more sensitive.

Quadracs

- Quadracs are a special type of thyristor which combines a "diac" and a "triac" in a single package.
- The diac is the triggering device for the triac.
- Quadracs eliminate the need to buy and assemble discrete parts.
- Quadracs are used in lighting control, speed control, and temperature modulation control applications.

Heat Sinks

- Small voltage drop exists at Thyristor Junctions.
- With flow of current, heat is developed at junctions.
- Junction temperature may increase beyond permissible limits.
- It may damage the Thyristor.
- To keep junction temperature within limits, Thyristor are mounted on Heat Sinks.

Thermal Ohm's Law

$$P21 = \frac{T2 - T1}{\theta 21}$$

- Θ₂₁ = Thermal Resistance between point 2 and 1
- P_{21} = Heat flow from point 2 and 1, W
- T_2 = Temperature of point 2, °C
- T_1 = Temperature of point 1, °C

Thermal Equivalent Circuit



Thermal Equivalent Circuit

- P_{av}: average power loss in the device
- T_j: Temperature of Junction
- T_c: Temperature of Case
- T_s: Temperature of Sink
- T_a: Ambient Temperature
- Θ_{jc}: Thermal Resistance from junction to case
- Θ_{cs} : Thermal Resistance from case to sink
- Θ_{sA} : Thermal Resistance from sink to atmosphere

- Normally Θ_{jc} and Θ_{cs} are specified by the manufacturer.
- Once P_{av} is known, the required Θ_{sA} is calculated for known T_{a.}
- Next step is to choose a heat sink and its size which would meet the thermal resistance requirement.
- Copper and Aluminum heat sinks are preffered.







Thyristor Tiggering

Forward Voltage Triggering

- When anode cathode increases beyond the forward break over voltage V_{BO}, reverse biased junction J₂ breaks down due to Avalache breakdown.
- Anode current is limited by load impedance only.

Gate Triggering

- Simple, reliable and efficient method to turn on the SCR and is mostly used.
- Positive gate voltage between gate and cathode is applied.
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- Reverse biased junction J2 no longer exists.
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dv/dt Triggering

- Reverse biased junction J₂ has characteristics similar to capacitor due to charges existing across the junction.
- If forward voltage is suddenly applied, the charging current through junction capacitance may turn on the SCR.

$$ic = \frac{dQ}{dt} = C\frac{dv}{dt}$$

dv/dt Triggering

- If rate of rise of forward voltage dv/dt is high, the charging current i_c would be more.
- This charging current plays the role of gate current.
- It may turn on the SCR even though gate signal is zero, at lower anode voltages.

Temperature Triggering

- Applied voltage, associated with leakage current raises the temperature of the junction J_{2.}
- With increase in temperature, width of depletion layer decreases.
- This further leads to more leakage current and therefore more junction temperature.

Temperature Triggering

 With the cumulative process, at some high temperature (Within the safe limits), depletion layer of reverse biased junction vanishes and device gets turned on.

Light Triggering



Light Triggering

- Light triggered SCRs has a recess made in the inner p-layer.
- When this recess is irradiated, free charge carriers are generated.
- With sufficient light at recess, the forward biased SCR is turned on.
- Such a thyristor is called Light Activated SCR (LASCR).
- LASCR may be triggered with a light source or with gate signal.

Triggering Circuits

Resistance Triggering



Resistance Triggering

- Simplest and most economical.
- Limited firing angle control (0-90°).
- The function of R₁ is to limit the gate current to safe value, as R₂ is varied.
- R₁ should be greater than or equal to V_m/I_{gm}. Where V_m is maximum source voltage and I_{gm} is maximum permissible gate current.







RC Half Wave Triggering Circuit



RC Half Wave Triggering Circuit

- By varying the value of R, firing angle can be controlled from 0 – 180°.
- In negative half, the capacitor charges through D2 with lower plate positive to voltage V_m.
- In positive half, capacitor C begins to charge through resistance R.
- When capacitor voltage reaches V_{gt}, SCR is fired.
- $[V_c = V.(1 e^{(-t/RC)})]$

Diode D₁ is used to prevent the breakdown of cathode to gate junction through D₂, during negative half cycle.





RC Full Wave Triggering Circuit







Unijunction Transistor (UJT)



- UJT is made of an n-type silicon base to which p-type emitter is embedded.
- n-type base is lightly doped, whereas p-type emitter is heavily doped.
- Between bases B₁ and B₂, unijunction behaves like an ordinary resistance.
- When V_{BB} is applied between B_1 and B_2

$$V_{AB1} = \frac{V_{BB}}{R_{B1} + R_{B2}} \cdot R_{B1} = \frac{R_{B1}}{R_{B1} + R_{B2}} \cdot V_{BB} = \eta \ V_{BB}$$
$\eta = \frac{RB1}{RB1 + RB2}$ is called the intrinsic standoff ratio.

- Typical values of η are 0.51 to 0.82.
- Inter base resistance RBB = RB1 + RB2 is of the order of 5 10 K Ω .
- Emitter is nearer to B₂, resistance R_{B2} is less than R_{B1}.







- As long as emitter voltage V_e < ηV_{BB}, the E-B₁ junction is reverse biased and emitter current I_e is negative.
- At point S, drop across R_E is zero and $I_e = 0$.
- When $Ve = \eta V_{BB} + V_D$ at point B, $E-B_1$ junction gets forward biased.
- VD is forward voltage drop across the junction E-B₁ (ususally 0.5V).
- V_p and I_p are called peak voltage and peak current respectively.

- At peak point B, the p-emitter begins to inject holes in to lower base region B₁.
- Resistance R_{B1} suddenly decreases.
- Potential of eta point A drops.
- As V_{EE} is constant, fall of V_e gives rise to more emitter current I_e (=(V_{EE} - V_e)/ R_E).
- Increased I_e injects more holes, further reducing R_{B1} and so on.

- Regenerative effect continues till R_{B1} has dropped to small value (from about $4K\Omega$ to around 2 to 25Ω).
- Emitter current is limited by external resistance R_E only.
- At valley point (point C), UJT reaches the on state.
- At point C, entire base region is saturated and R_{B1} can not decrease any more.

- Any increase in V_e is accompanied by increase in I_e.
- Between point B and C, V_e Falls and I_e increases.
- UJT, therefore, exhibits negative resistance between point B and C.

UJT Relaxation Oscillator





- UJT is highly efficient switch.
- Switching time is of the range of nano seconds.
- Because of negative resistance characteristics,
 UJT can be used as relaxation oscillator.
- External resistance R₁ and R₂ are small as compared to internal resistances R_{B1} and R_{B2}.
- On application of V_{BB}, capacitor C begins to charge through R, exponentially towards V_{BB}.

Commutation of Thyristor

Class A Commutation (Load Commutation)









Class B Commutation (Resonant Pulse Commutation)



Class C Commutation (Complementry Commutation)



R R_2 Vs $v_c +$ $\nu_{T_2} = \nu_c$ 1= i1+ic

Class D Commutation: Impulse Commutation



Class E Commutation: External Pulse Commutation



Class F or Line Commutation





Series and Parallel Operation

string efficiency

Actual voltage/current rating of the whole string

[Individual voltage/current rating of one SCR] [Number of SCRs in the string]

DRF = 1 - string efficiency

Series Operation





Parallel Operation





Applications of Thyristor

Light intensity Control


Fan Speed Cntrol



Speed Control of DC Motor



Battery Charger



Automatic Street Light



SCR Protection

dv/dt Protection (Snubber Ckt)



di/dt Protection



di/dt Protection



Complete Protection Ckt.







